

Components for low-voltage surge protection - Part
341: Performance requirements and test circuits for
thyristor surge suppressors (TSS)

EESTI STANDARDI EESSÕNA

NATIONAL FOREWORD

See Eesti standard EVS-EN IEC 61643-341:2020 sisaldab Euroopa standardi EN IEC 61643-341:2020 ingliskeelset teksti.	This Estonian standard EVS-EN IEC 61643-341:2020 consists of the English text of the European standard EN IEC 61643-341:2020.
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English Version

**Components for low-voltage surge protection - Part 341:
Performance requirements and test circuits for thyristor surge
suppressors (TSS)
(IEC 61643-341:2020)**

Composants pour parafoudres basse tension - Partie 341:
Exigences de performance et circuits d'essai pour
parafoudres à thyristor (TSS)
(IEC 61643-341:2020)

Bauelemente für Überspannungsschutzgeräte für
Niederspannung - Teil 341: Leistungsanforderungen sowie
Prüfschaltungen für Suppressordioden (TSS)
(IEC 61643-341:2020)

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European foreword

The text of document 37B/218/FDIS, future edition 2 of IEC 61643-341, prepared by SC 37B "Components for low-voltage surge protection" of IEC/TC 37 "Surge arresters" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 61643-341:2020.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2021-03-17
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2023-06-17

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IEC 60060-1:2010	NOTE	Harmonized as EN 60060-1:2010 (not modified)
IEC 60068-2-20:2008	NOTE	Harmonized as EN 60068-2-20:2008 (not modified)
IEC 60068-2-21:2006	NOTE	Harmonized as EN 60068-2-21:2006 (not modified)
IEC 60099-4:2014	NOTE	Harmonized as EN 60099-4:2014 (not modified)
IEC 60721-3-3:2019	NOTE	Harmonized as EN IEC 60721-3-3:2019 (not modified)
IEC 60721-3-9:1993	NOTE	Harmonized as EN 60721-3-9:1993 (not modified)
IEC 60749-1:2002	NOTE	Harmonized as EN 60749-1:2003 (not modified)
IEC 60950-1:2005	NOTE	Harmonized as EN 60950-1:2006 (modified)
IEC 61000-4-5:2014	NOTE	Harmonized as EN 61000-4-5:2014 (not modified)
IEC 61643-11:2011	NOTE	Harmonized as EN 61643-11:2012 (modified)
IEC 62475:2010	NOTE	Harmonized as EN 62475:2010 (not modified)

Annex ZA

(normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050-521	-	International Electrotechnical Vocabulary - Part 521: Semiconductor devices and integrated circuits	-	-
IEC 60068-2-20	2008	Environmental testing - Part 2-20: Tests - Test T: Test methods for solderability and resistance to soldering heat of devices with leads	EN 60068-2-20	2008

INTERNATIONAL STANDARD

NORME INTERNATIONALE

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for thyristor surge suppressors (TSS)**

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International Standard IEC 61643-341 has been prepared by subcommittee 37B, Components for low-voltage surge protection, of IEC technical committee 37: Surge arresters.

This second edition of IEC 61643-341 cancels and replaces the first edition published in 2001. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition: Addition of performance values.

The text of this standard is based on the following documents:

FDIS	Report on voting
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Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

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